## Application/Control No. Applicant(s)/Patent Under Reexamination 10/766,710 LEE, HEON Notice of References Cited Art Unit Examiner Page 1 of 1 1765 Kin-Chan Chen **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name Country Code-Number-Kind Code MM-YYYY US-2005/0161431 07-2005 Lee, Heon 216/054 US-2004/0266064 12-2004 Davison, Peter A. 438/120 В \* US-2004/0211754 10-2004 Sreenivasan, Sidlgata V. 216/041 С \* 216/54 US-6,755,984 06-2004 Lee et al. D \* US-6,671,034 12-2003 Hatakeyama et al. 355/67 Ε \* US-2003/0205657 11-2003 Voisin, Ronald D. 249/187.1 F \* US-2003/0141276 07-2003 Lee, Heon 216/8 G US-Н US-US-US-US-US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W Х

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